

TAILONG SHI

3D Systems Packaging Research Center
Georgia Institute of Technology
tshi@gatech.edu
(408) 387-2200

EDUCATION

- Georgia Institute of Technology**, Atlanta, Georgia, USA 08/2014 - present
Doctor of Philosophy in Electrical and Computer Engineering,
- Santa Clara University**, Santa Clara, California, USA 09/2012 - 06/2014
Master of Science in Electrical Engineering, GPA: 3.87/4.0
- Southeast University**, Nanjing, China 08/2008 - 06/2012
Bachelor of Engineering in Information Engineering, GPA: 83.1/100

RESEARCH EXPERIENCE

Georgia Institute of Technology, Atlanta, Georgia, USA
Graduate Research Assistant in 3D Systems Packaging Research Center

Project: 2D Ultra-thin Glass Mobile BGA Package 2014 - 2016

- Designed and demonstrated a four-metal layer 140 μm thick fully-integrated single-chip glass BGA package at 40/80 μm off-chip I/O pitch with through-package vias (TPVs) at 160 μm pitch for mobile applications.
 - Designed nine types of multi-level test structures to evaluate the yield at each fabrication process step, including through-package vias daisy chains, micro-vias daisy chains, chip-level interconnection daisy chains, and other multi-layer test structures.
 - Designed each layer's layout of the fully-integrated package using AutoCAD, including the through package vias layer, four metal layers, two micro-vias layers, and two passivation layers. Panelized the 15mm x 15mm coupon design to fit in a 150mm x 150mm panel with alignment mark design on each layer.
 - Fabricated the four layer fully-integrated glass package on 100 μm thick low coefficient of thermal expansion (CTE) glass panels with 160 μm pitch through-package vias (TPVs), using advanced semi-additive process (SAP) for multilayer RDLs and micro-vias.
 - Achieved over 99% TPV yield at 160 μm pitch by advanced via-first processes with plasma etching primer opening method.
 - Demonstrated chip-level assembly by standard Cu pillar thermos-compression bonding (TCB) process on substrate strips at 40/80 μm off-chip I/O pitch.
 - Demonstrated for the first time the DC signal transmission from the die at 40/80 μm I/O pitch, through a 100 μm -thick glass package with TPVs and multilayered wiring, to the board and back.

Project: Glass Panel Embedding Package 2016 - 2018

- Demonstrated for first time an ultra-thin, panel-level glass fan-out package to serve as the next generation of fan-out packaging for high density digital and high performance analog, power, RF and mm-wave applications.
 - Designed and demonstrated an ultra-thin panel-level glass fan-out package with total thickness less than 215 μm , including 50 μm thick glass carrier, 70 μm thick glass cavity panel, 75 μm thick test chips embedded in the glass cavity, bonding dry film and the double-side RDL layers.
 - Process development and optimization including glass-to-glass bonding, die placement into glass cavity, surface planarization and chip-package microvia laser drilling.
 - Proposed 77GHz Radar Module with advanced panel-level glass fan-out structure.
 - Modeled chip-to-package interconnection loss of the panel-level glass fan-out architecture for high frequency applications.

SKILLS

Software: AutoCAD, HFSS, SONNET, Keysight ADS, CAM, MATLAB

MAJOR PUBLICATIONS

T. Shi *et al.*, "Design, Demonstration and Characterization of Ultra-Thin Low-Warpage Glass BGA Packages for Smart Mobile Application Processor," in *66th IEEE Electronic Components and Technology Conference, (ECTC) 2016*, May 31, 2016 - June 3, 2016, Las Vegas, NV, United States, 2016, pp. 1465-1470

T. Shi *et al.*, "First Demonstration of Panel Glass Fan-Out (GFO) Packages for High I/O Density and High Frequency Multi-chip Integration," *2017 IEEE 67th Electronic Components and Technology Conference (ECTC)*, Orlando, FL, 2017, pp. 41-46.

T. Shi *et al.*, "Next Generation of Automotive Radar with Leading-edge Advances in SiGe Devices and Glass Panel Embedding Packaging," accepted in *2018 IEEE 68th Electronic Components and Technology Conference (ECTC)*.

T. Shi *et al.*, "Tracing vocal fold vibrations using level set segmentation method," *International journal for numerical methods in biomedical engineering* 31.6 (2015).